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Express Mail No. EV 346 812 661 US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Bruno GHYSELEN et al.

Confirmation No. 9064

Application No: 10/637,094

Group Art Unit: 2812

Filing Date: August 6, 2003

Examiner: Thanh V. Pham

Atty. Docket No.: 4717-6300

For: METHOD AND APPARATUS FOR
ADJUSTING THE THICKNESS OF A LAYER
OF SEMICONDUCTOR MATERIAL

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed is a copy of a further reference, U.S. patent 5,689,614, for the Examiner's review and consideration. This reference is listed on the enclosed Form PTO-1449. It is respectfully requested that these references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

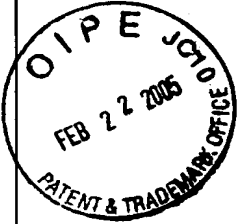
No fee is believed to be due for the filing of this statement as it is being submitted prior to a first action on the merits of the claims in this application. Should any fee be required, however, please charge the required fee to Winston & Strawn Deposit Account No. 50-1814.

Respectfully submitted,

Date: 2/22/05


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				ATTY. DOCKET NO.:		APPLICATION NO.:	
				87534-6300		10/637,094	
				APPLICANT:			
				Bruno GHYSELEN et al.			
FILING DATE:				GROUP:			
August 6, 2003				2812			
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,689,614	11/1997	Gronet et al.	392	416	
	AB						
	AC						
	AD						
	AE						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
	AF						
	AG						
	AH						
	AI						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AJ						
	AK						
	AL						
	AM						
	AN						
	AO						
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609 ; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							